QM LAB

Standards under the Accreditation with Flexible Scope

inventronics

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Scope of accreditation by DAkkS:	https://www.dakks.de/files/data/as/pdf/D-PL-22414-01-00.pdf
Public LAB flexible scope	Lab as a Service – Inventronics
Category:	A
Department:	SEB, EMV

The standard test methods listed in this document can be applied by the testing laboratory with deviating issue dates from the standard test methods listed by DAkkS under the laboratory's accreditation number. According to DAkkS regulation R-17025-PL the laboratory is permitted to apply these listed methods without additional prior information and approval by DAkkS.

Department	Standard / test method / date of issue	Title of the standard or test procedure	Limitation of test method
SEB	IEC 61347-1:2024	Controlgear for electric light sources – Safety – Part 1: General requirements	Annex I (Reduction of creepage distances and clearances for coated or potted controlgear) Mandrel test acc. IEC 61558-1 cl. 26.3.4 & IEC 61347 Annex H
SEB	IEC 61347-2-11:2024	Part 2-11: Particular requirements – Miscellaneous electronic circuits used with luminaires	Annex I (Reduction of creepage distances and clearances for coated or potted controlgear) Mandrel test acc. IEC 61558-1 cl. 26.3.4 & IEC 61347 Annex H
SEB	IEC 61347-2-13:2024	Part 2-13: Particular requirements - Electronic controlgear for LED light source	Annex I (Reduction of creepage distances and clearances for coated or potted controlgear) Mandrel test acc. IEC 61558-1 cl. 26.3.4 & IEC 61347 Annex H

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Document history

Changes of previous versions are shaded in gray.

Version	Date	Short description of changes	Process Expert
08	07/2025	Adding measurement uncertainty	Schemmel
09	08/2025	Using new template, complete rework due to DAKKS nonconformity	Rank
10	09/2025	Adding IEC 61347-1:2024; Adding Exclusion: Annex I Adding IEC 61347-2-11:2024 Adding IEC 61347-2-13:2024	Rank

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